

1. Record Nr.	UNINA9910824189103321
Titolo	Electron microscopy XIV : selected, peer reviewed papers from the XIV International Conference on Electron Microscopy (EM2011), June 26-30, 2011, Wisla, Poland // edited by Danuta Stroz and Krystian Prusik
Pubbl/distr/stampa	Durnten-Zurich, Switzerland ; ; Enfield, NH, USA : , : TTP, , [2012] ©2012
ISBN	3-03813-699-9
Descrizione fisica	1 online resource (352 p.)
Collana	Solid state phenomena, , 1012-0394 ; ; volumes 186
Altri autori (Persone)	StrozDanuta PrusikKrystian
Disciplina	502.825
Soggetti	Electron microscopy
Lingua di pubblicazione	Inglese
Formato	Materiale a stampa
Livello bibliografico	Monografia
Note generali	Description based upon print version of record.
Nota di bibliografia	Includes bibliographical references and indexes.
Nota di contenuto	Electron Microscopy XIV; Preface and Conference Photo; Table of Contents; Methods of Electron Crystallography as Tools for Materials Analysis; Characterization of Grain Boundary Geometry in the TEM, Exemplified in Si Thin Films; Orientation and Phase Mapping in TEM Microscopy (EBSD-TEM Like): Applications to Materials Science; The Art and Application of Large Angle Convergent Beam Electron Diffraction; Cathodoluminescence and Electroluminescence of Semiconductor Structures in SEM; Secondary Electron Detector with the Unipotential Lens Structure for Variable Pressure/Environmental SEM A Quantitative Analytical Method for the Identification and Characterization of Mineralized Nanoparticles in Food Supplements Physical and Chemical Studies of Bacterial Bioaerosols at Wastewater Treatment Plant Using Scanning Electron Mikroskopy and X-Ray Photoelectron Spectroscopy; 3D Imaging and Metrology of Yttria Dispersoids in INCOLOY MA956 by Electron Tomography; 3D Imaging of Strengthening Particles in Cr-V-Mo (13HMF) Steel Using FIB/SEM Tomography; Three-Dimensional Visualization and Metrology of Nanoparticles in Inconel 718 by Electron Tomography Martensitic Transformation in Ti50Ni25Cu25 Shape Memory Alloy Studied by EBSD Investigations of Fine Grained Metallic Materials by Means of Orientation Maps in Transmission Electron Microscope; Phase

Identification in Nickel-Based Superalloys Using EBSD/SEM and Electron
 Diffraction in STEM; High Resolution EBSD/SEM Analysis of PLZT
 Ferroelectric Crystals in Low Vacuum Conditions - A few Practical
 Remarks; Study of Silicon Nanoparticles Formation in Silicon Nitride;
 Structural and Chemical Characterization of Al(Ga)N/GaN Quantum Well
 Structures Grown by Plasma Assisted Molecular Beam Epitaxy
 Wurtzite-to Amorphous-to Cubic Phase Transition of GaN1-XAsx
 Alloys with Increasing as Content Study of Oxides Formed in HfO2/Si
 Structure for High-k Dielectric Applications; Ni-Based Ohmic Contacts
 to Silicon Carbide Examined by Electron Microscopy; Crystallization and
 Microstructure of Co_{0.75}Ni_{0.25}Si₂ Solid Solution; Nanotexture Studies
 of NiTi Shape Memory Alloy after Severe Plastic Deformation with the
 Use of TEM; SEM EBSD and TEM Structure Studies of α -Brass after
 Severe Plastic Deformation Using Equal Channel Rolling Followed by
 Groove Pressing
 Crystallographic Aspects of Deformation and Recrystallization in ECAP-
 Processed AA3104 Aluminium Alloy Microstructure of the Ni-W Solid
 Solution Prepared by Levitation and after High Pressure Torsion Severe
 Plastic Deformation; Near Grain Boundary Behavior of Aluminum
 Bicrystals Deformed in Plane Strain Conditions; Microstructure and
 Texture Evolutions in AA1200 Aluminum Alloy Deformed by
 Accumulative Roll Bonding Method; Gradient Microstructure of
 FeCr₃₀Co₈ Hard Magnetic Alloy Subjected to Plastic Deformation by
 Tension Combined with Torsion at 700 and 720°C
 Effect of Rapid Solidification on the Structure and Mechanical Properties
 of AZ91 Magnesium Alloy

Sommario/riassunto

These are the proceedings of the XIV International Conference on
 Electron Microscopy (EM2011) held in Wisla, Poland from the 26 to 30th
 June 2011. The goal of the conference was to provide a forum where
 researchers from many different countries could exchange their latest
 advances in the field of structural studies, regarding the use of electron
 microscopic techniques as applied to various materials. Plenary and
 invited lectures offered overviews of exciting new developments which
 highlighted the applications of new electron microscopic techniques in
 physics, chemistry, materials science and i
